

<b>Notice of References Cited</b>		Application/Control No. 10/530,169	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
		Examiner DEAN KWAK	Art Unit 1797	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,324,069 A	06-1967	KOBLITZ FRANK F et al.	524/296
*	B	US-5,130,201 A	07-1992	Yoshimura et al.	428/416
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	GB 2292699 A	03-1996	United Kingdom	USUI, MASAYOSHI	F16L 58/04
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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